

# RELIABILITY REPORT



## RELIABILITY DATA

### LT1311

### 8/21/2006

#### • OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(1)</sup> AT +125°C	NUMBER OF <sup>(2)</sup> FAILURES
SOIC/SOT/MSOP	40	9513	9526	99.01	0
	40			99.01	0

#### • PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
PLASTIC DIP SOIC/SOT/MSOP	50	9635	9635	1.20	0
	214	9520	0205	79.73	0
	264			80.93	0

#### • TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	206	9520	0205	183.60	0
	206			183.60	0

#### • THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	84	9604	0142	56.43	0
	84			56.43	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 18.58 FITS

(3) Mean Time Between Failures in Years = 6,140

Note: 1 FIT = 1 Failure in One Billion Hours.